

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/824,184	MURAYAMA ET AL.	
Examiner	Art Unit	
Chuck Mah	3677	

SEARCHED				
Class	Subclass	Date	Examiner	
16	82 86A			
	86b 86c			
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292	270 269 268			
	269			
	268			
	266			
29/2	146,11			
	146.1	2 7/21/07	ap	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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